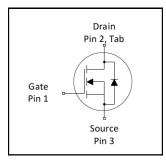
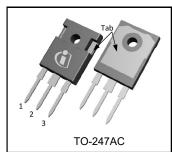
# IRFP4668PbF



V <sub>DSS</sub>	200V
R <sub>DS(on)</sub> typ.	8.0mΩ
max.	9.7m $\Omega$
I <sub>D</sub>	130A





# **Applications**

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

#### **Benefits**

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free

Base Part Number	Package Type	Standard	Orderable Part Number	
		Form	Quantity	
IRFP4668PbF	TO-247AC	Tube	25	IRFP4668PbF

**Absolute Maximum Ratings** 

Symbol	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	130		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	92	Α	
I <sub>DM</sub>	Pulsed Drain Current ①	520		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	520	W	
	Linear Derating Factor	3.5	W/°C	
$V_{GS}$	Gate-to-Source Voltage	± 30	V	
dv/dt	Peak Diode Recovery ③	57	V/ns	
T <sub>J</sub>	Operating Junction and	FF 4- 1 47F		
$T_{STG}$	Storage Temperature Range	-55 to + 175	°C	
	Soldering Temperature, for 10 seconds (1.6mm from case)	300		
	Mounting torque, 6-32 or M3 screw	10lbf⋅in (1.1N⋅m)		

# **Avalanche Characteristics**

E <sub>AS</sub> (Thermally limited)	Single Pulse Avalanche Energy ②	760	mJ
I <sub>AR</sub>	Avalanche Current ①	Con Fig. 14, 15, 22a, 22b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ①	See Fig. 14, 15, 22a, 22b	mJ

# **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		0.29	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface	0.24		°C/W
$R_{\theta JA}$	Junction-to-Ambient⑦®		40	



### Static @ $T_J = 25^{\circ}C$ (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	200			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.21		V/°C	Reference to 25°C, I <sub>D</sub> = 5mA①
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		8.0	9.7	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 81A ④
$V_{GS(th)}$	Gate Threshold Voltage	3.0		5.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
	Drain-to-Source Leakage Current			20	μA	$V_{DS} = 200V, V_{GS} = 0V$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 200V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
$I_{GSS}$	Gate-to-Source Reverse Leakage			-100	IIA	$V_{GS} = -20V$
$R_G$	Internal Gate Resistance		1.0		Ω	

# Dynamic @ T<sub>J</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	150			S	$V_{DS} = 50V, I_{D} = 81A$
$\overline{Q_g}$	Total Gate Charge		161	241		I <sub>D</sub> = 81A
$Q_{gs}$	Gate-to-Source Charge		54		nC	V <sub>DS</sub> =100V
$Q_{gd}$	Gate-to-Drain ("Miller") Charge		52		l IIC	V <sub>GS</sub> = 10V ④
Q <sub>sync</sub>	Total Gate Charge Sync. (Q <sub>g</sub> - Q <sub>gd</sub> )		109			$I_D = 81A, V_{DS} = 0V, V_{GS} = 10V$
$t_{d(on)}$	Turn-On Delay Time		41			V <sub>DD</sub> = 130V
t <sub>r</sub>	Rise Time		105			I <sub>D</sub> = 81A
$t_{d(off)}$	Turn-Off Delay Time		64		ns	$R_G = 2.7\Omega$
t <sub>f</sub>	Fall Time		74			V <sub>GS</sub> = 10V ④
C <sub>iss</sub>	Input Capacitance		10720			$V_{GS} = 0V$
Coss	Output Capacitance		810			$V_{DS} = 50V$
C <sub>rss</sub>	Reverse Transfer Capacitance		160			f = 1.0  MHz,  See Fig. 5
C <sub>oss</sub> eff. (ER)	Effective Output Capacitance (Energy Related) ®		630		pF	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 160V $
C <sub>oss</sub> eff. (TR)	Effective Output Capacitance (Time Related)®		790			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 160V $

# **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Cond	itions	
Is	Continuous Source Current			120	Α	MOSFET symbol	D	
	(Body Diode)			130	A	showing the		
I <sub>SM</sub>	Pulsed Source Current			520	Α	integral reverse	G T	
	(Body Diode) ①			320	A	p-n junction diode.	s	
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 81A$	, $V_{GS} = 0V \oplus$	
t <sub>rr</sub>	Reverse Recovery Time		130		no	T <sub>J</sub> = 25°C	\/ - 400\/	
			155		ns	T <sub>J</sub> = 125°C	$V_R = 100V$ , $I_F = 81A$	
$Q_{rr}$	Reverse Recovery Charge		633		nC	$T_J = 25^{\circ}C$	di/dt = 100A/µs ④	
			944		IIC	$T_J = 125^{\circ}C$		
$I_{RRM}$	Reverse Recovery Current		8.7		Α	T <sub>J</sub> = 25°C		
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )						

#### Notes:

- ① Repetitive rating; pulse width limited by max. Junction temperature.
- ③  $I_{SD} \le 81$ A, di/dt  $\le 520$ A/ $\mu$ s,  $V_{DD} \le V_{(BR)DSS}$ ,  $T_J \le 175$ °C. ④ Pulse width  $\le 400$  $\mu$ s; duty cycle  $\le 2$ %.
- © Coss eff. (TR) is a fixed capacitance that gives the same charging time as Coss while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- © Coss eff. (ER) is a fixed capacitance that gives the same energy as Coss while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- ② When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques.
- ® R<sub>θ</sub> is measured at T<sub>J</sub> approximately 90°C.



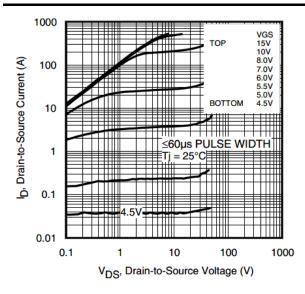


Fig 1. Typical Output Characteristics

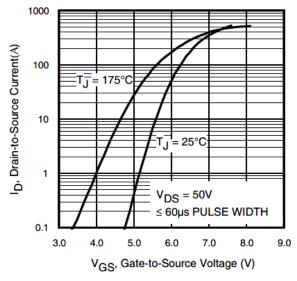


Fig 3. Typical Transfer Characteristics

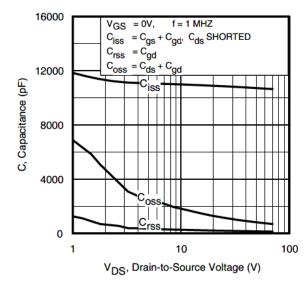


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

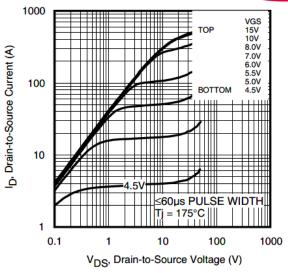


Fig 2. Typical Output Characteristics

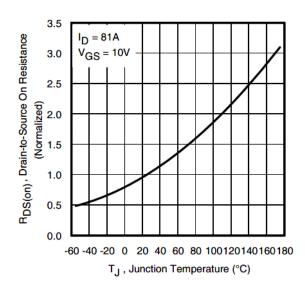


Fig 4. Normalized On-Resistance vs. Temperature

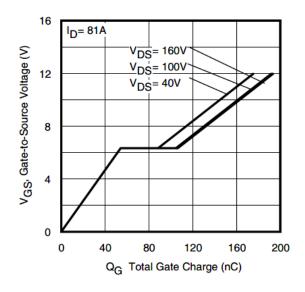
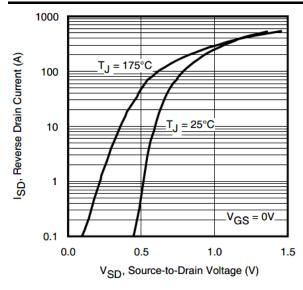


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage





**Fig 7.** Typical Source-to-Drain Diode Forward Voltage

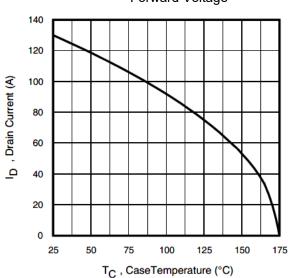


Fig 9. Maximum Drain Current vs. Case Temperature

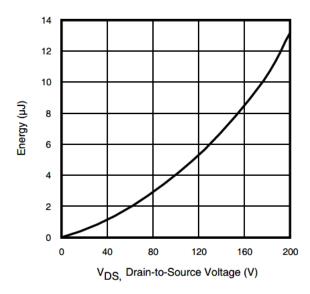


Fig 11. Typical Coss Stored Energy

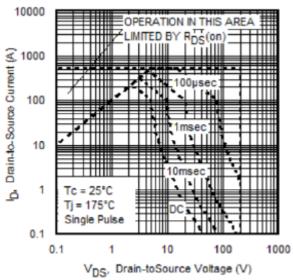


Fig 8. Maximum Safe Operating Area

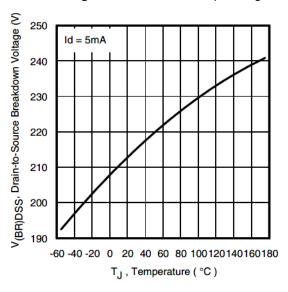


Fig 10. Drain-to-Source Breakdown Voltage

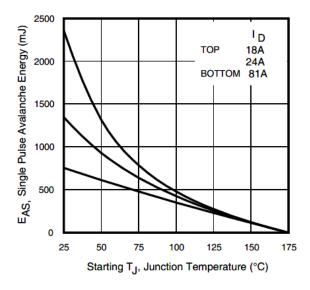


Fig 12. Maximum Avalanche Energy vs. Drain Current



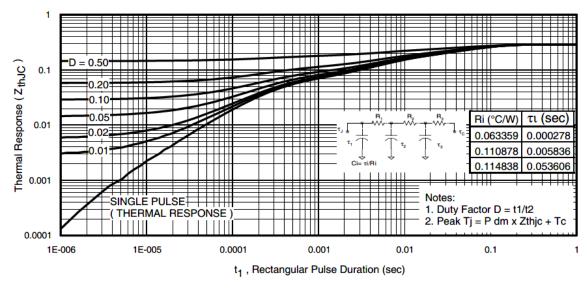


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

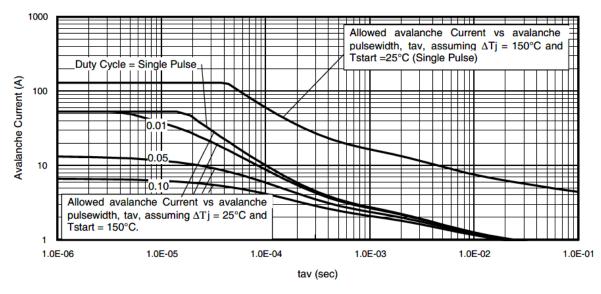


Fig 14. Typical Avalanche Current vs. Pulsewidth

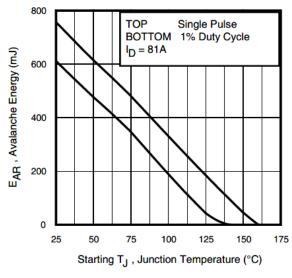


Fig 15. Maximum Avalanche Energy vs. Temperature

#### Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature
- far in excess of Timax. This is validated for every part type. 2. Safe operation in Avalanche is allowed as long as Tjmax is not
- exceeded. 3. Equation below based on circuit and waveforms shown in Figures
- 16a, 16b. 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed Timax (assumed as 25°C in Figure 14, 15).
  - t<sub>av</sub> = Average time in avalanche.
  - D = Duty cycle in avalanche = tav ·f  $Z_{th,JC}(D, t_{av})$  = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



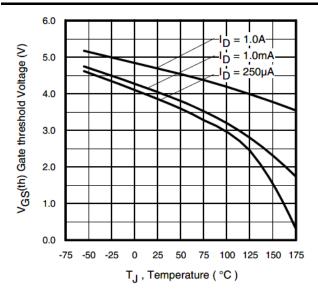


Fig. 16 Threshold Voltage vs. Temperature

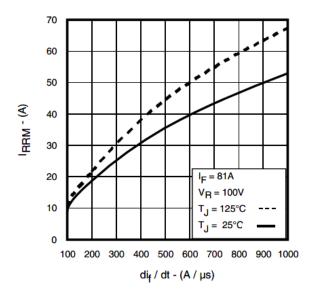


Fig 18. Typical Recovery Current vs. di<sub>f</sub>/dt

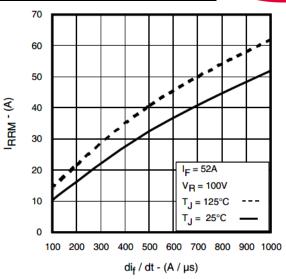


Fig. 17 Typical Recovery Current vs. di<sub>f</sub>/dt

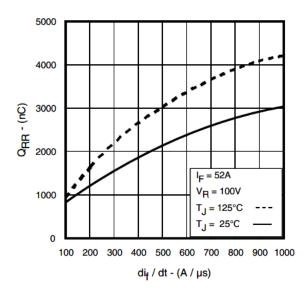


Fig 19. Typical Stored Charge vs. di<sub>f</sub>/dt

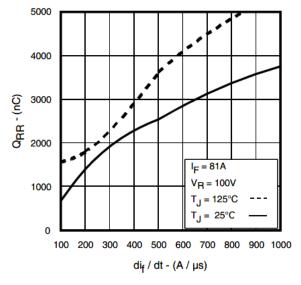
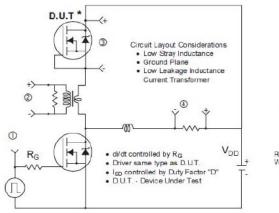
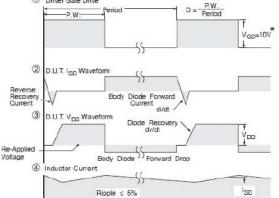


Fig 20. Typical Stored Charge vs. di<sub>f</sub>/dt







\* V<sub>GS</sub> = 5V for Logic Level Devices

1 Driver Gate Drive

Fig 21. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

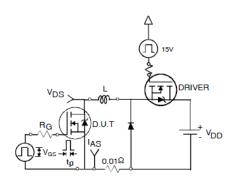


Fig 22a. Unclamped Inductive Test Circuit

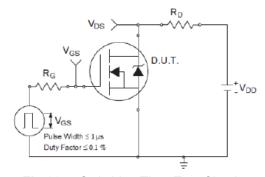


Fig 23a. Switching Time Test Circuit

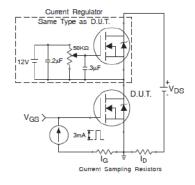


Fig 24a. Gate Charge Test Circuit

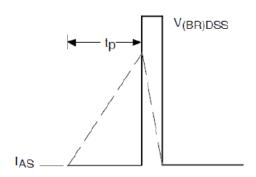


Fig 22b. Unclamped Inductive Waveforms

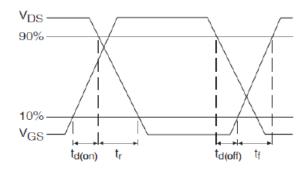


Fig 23b. Switching Time Waveforms

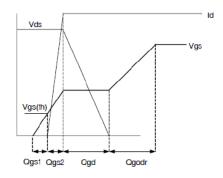
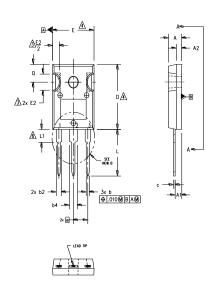


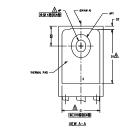
Fig 24b. Gate Charge Waveform

<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel

# infineon

# TO-247AC Package Outline (Dimensions are









**TO-247AC Part Marking Information** 

#### NOTES:

1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M 1994.

2. DIMENSIONS ARE SHOWN IN INCHES.

CONTOUR OF SLOT OPTIONAL.

, DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127)
PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

5\ THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS D1 & E1.

LEAD FINISH UNCONTROLLED IN L1.

OP TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5 \* TO THE TOP OF THE PART WITH A MAXIMUM HOLE DIAMETER OF .154 INCH.

8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-247AC .

SYMBOL	INC	HES	MILLIM	ETERS	
	MIN. MAX.		MIN.	MAX.	NOTES
Α	.183	.209	4.65	5.31	
A1	.087	.102	2.21	2.59	
A2	.059	.098	1.50	2.49	
b	.039	.055	0.99	1.40	
b1	.039	.053	0.99	1.35	
b2	.065	.094	1.65	2.39	
b3	.065	.092	1.65	2.34	
b4	.102	.135	2.59	3.43	
b5	.102	.133	2.59	3.38	
С	.015	.035	0.38	0.89	
c1	.015	.033	0.38	0.84	
D	.776	.815	19.71	20.70	4
D1	.515	-	13.08	-	5
D2	.020	.053	0.51	1.35	
E	.602	.625	15.29	15.87	4
E1	.530	-	13.46	-	
E2	.178	.216	4.52	5.49	
e	.215 BSC		5.46	BSC	
Øk	.0	10	0.	25	
L	.559	.634	14.20	16.10	
L1	.146	.169	3.71	4.29	
øΡ	.140	.144	3.56	3.66	
øP1	-	.291	-	7.39	
Q	.209	.224	5.31	5.69	
S	.217	BSC	5.51	BSC	
			1		

# LEAD ASSIGNMENTS

#### <u>HEXFET</u>

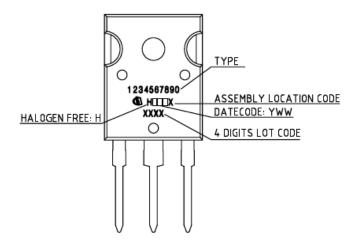
- 1.- GATE
- 2.- DRAIN 3.- SOURCE
- 4. DRAIN

#### IGBTs, CoPACK

- 1.- GATE
- 2.- COLLECTOR 3.- EMITTER
- 4.- COLLECTOR

## DIODES

- 1.- ANODE/OPEN
- 2.- CATHODE
- 3.- ANODE



TO-247AC package is not recommended for Surface Mount Application.



#### **Revision History**

Date	Rev.	Comments
		Changed datasheet to Infineon format
12/02/2021	2.1	<ul> <li>Corrected 10ms and 1ms labels of Fig.8_SOA curve</li> </ul>
		Added disclaimer on last page.
10/30/2024	2.2	Updated Part marking –page 8

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